

MIL-STD-750D

METHOD 1032.2

HIGH-TEMPERATURE (NONOPERATING) LIFE (SAMPLE PLAN)

1. Purpose. The purpose of this test is to determine compliance with the specified sample plan for devices subjected to the specified conditions.

2. Procedure. Unless otherwise specified, the device shall be stored under the specified ambient conditions (normally the maximum temperature) 340 hours minimum. The sample units shall be removed from the specified ambient conditions and allowed to reach standard test conditions. Specified end-point measurements for qualification and quality conformance inspection shall be completed within 96 hours after removal of sample units from the specified ambient conditions. If measurements cannot be performed within the specified time, the devices shall be subjected to the same test conditions for a minimum of 24 hours before post test measurements are performed. Additional readings may be taken at the discretion of the manufacturer.

2.1 Visual examination. The markings shall be legible after the test. There shall be no evidence (when examined without magnification) of flaking or pitting of the finish or corrosion that will interfere with the mechanical and electrical application of the device.

3. Summary. The following conditions shall be specified in the detail specification:

- a. Test conditions (see 2.).
- b. Test time, if other than 340 hours (see 2.).
- c. End point measurements (see 2.).